

First Named Inventor	Ravi Iyer
Serial No.	10/689,894
Filing Date	October 21, 2003
Group Art Unit	2822
Examiner Name	Unknown
Attorney Docket No.	400.083US03
Title: COMPOUND STRUCTURE FOR REDUCED CONTACT RESISTANCE	

**SUPPLEMENTAL  
INFORMATION DISCLOSURE  
STATEMENT  
FORM PTO-1449**

Sheet 1 of 1



Other References	
Examiner Initials	Author, Title, Date, Pages, etc.

Examiner Signature		Date Considered	12/13/05
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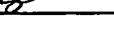
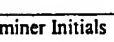
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First Named Inventor	Ravi Iyer	<b>INFORMATION DISCLOSURE STATEMENT FORM PTO-1449</b>
Serial No.	Unknown	
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Confirmation No.	Unknown	
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Title: COMPOUND STRUCTURE FOR REDUCED CONTACT RESISTANCE		Sheet 1 of 1

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Examiner Initials	Foreign Patent		Name	Publication Date
	Country	No.		

<b>Other References</b>	
Examiner Initials	Author, Title, Date, Pages, etc.

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